Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/667,029	ALFERNESS ET AL.
Examiner	Art Unit
 Tanh Q. Nguyen	2182

SEARCHED						
Class	Subclass	Date	Examiner			
710	5,6,8,15-18 29,36,58 60,104	03/14/06	TON			
711 370	29,36,58 60,104 150,170 231,235 325,395.21					
	395.41,398 437,461,					
limited		<b>V</b>	V			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
inventor seach-East/eDAN Cartinity-PATM East Search-Results attached	03/13/06 1 03/14/06 03/15/06	TON	